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Form PTO 1449	ATTY. DOCKET NUMBER	SERIAL NUMBER
U.S. Department of Commerce	358275.30005	10/576,879
	APPLICANT	NOV 21 1006 W
Patent and Trademark Office	TANAKA, et. al.	NOV 2
Information Disclosure Statement by Applicant	FILING DATE	GROUP C
	April 21, 2006	CATE TRADEMENT

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EXAMINER /Sheeba Ahmed/

DATE CONSIDERED 03/30/2008

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PTO1449

